Preferred Device

# **Sensitive Gate Silicon Controlled Rectifiers**

# **Reverse Blocking Thyristors**

Designed for high volume, low cost, industrial and consumer applications such as motor control; process control; temperature, light and speed control.

## **Features**

- Small Size
- Passivated Die for Reliability and Uniformity
- Low Level Triggering and Holding Characteristics
- Available in Two Package Styles
   Surface Mount Lead Form Case 369C
   Miniature Plastic Package Straight Leads Case 369
- Epoxy Meets UL 94 V-0 @ 0.125 in
- ESD Ratings: Human Body Model, 3B > 8000 V Machine Model, C > 400 V
- Pb-Free Packages are Available

## MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Peak Repetitive Off–State Voltage (Note 1) (T <sub>J</sub> = -40 to 110°C, Sine Wave, 50 to 60 Hz, Gate Open) MCR8DSM MCR8DSN	V <sub>DRM,</sub> V <sub>RRM</sub>	600 800	V
On–State RMS Current (180° Conduction Angles; T <sub>C</sub> = 90°C)	I <sub>T(RMS)</sub>	8.0	Α
Average On–State Current (180° Conduction Angles; T <sub>C</sub> = 90°C)	I <sub>T(AV)</sub>	5.1	Α
Peak Non-Repetitive Surge Current (1/2 Cycle, Sine Wave 60 Hz, T <sub>J</sub> = 110°C)	I <sub>TSM</sub>	90	Α
Circuit Fusing Consideration (t = 8.3 msec)	l <sup>2</sup> t	34	A <sup>2</sup> sec
Forward Peak Gate Power (Pulse Width $\leq$ 1.0 $\mu$ sec, $T_C = 90^{\circ}C$ )	P <sub>GM</sub>	5.0	W
Forward Average Gate Power (t = 8.3 msec, T <sub>C</sub> = 90°C)	P <sub>G(AV)</sub>	0.5	W
Forward Peak Gate Current (Pulse Width ≤ 1.0 µsec, T <sub>C</sub> = 90°C)	I <sub>GM</sub>	2.0	А
Operating Junction Temperature Range	TJ	-40 to 110	°C
Storage Temperature Range	T <sub>stg</sub>	-40 to 150	°C

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

1. V<sub>DRM</sub> and V<sub>RRM</sub> for all types can be applied on a continuous basis. Ratings apply for negative gate voltage; positive gate voltage shall not be applied concurrent with negative potential on the anode. Blocking voltages shall not be tested with a constant current source such that the voltage ratings of the device are exceeded.



# ON Semiconductor®

http://onsemi.com

# SCRs 8 AMPERES RMS 600 – 800 VOLTS



#### MARKING DIAGRAM



DPAK CASE 369C STYLE 4



PIN ASSIGNMENT		
1	Cathode	
2	Anode	
3	Gate	
4	Anode	

# **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 2 of this data sheet.

**Preferred** devices are recommended choices for future use and best overall value.

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## THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance - Junction-to-Case - Junction-to-Ambient - Junction-to-Ambient (Note 2)	$egin{array}{l} R_{ hetaJC} \ R_{ hetaJA} \ R_{ hetaJA} \end{array}$	2.2 88 80	°C/W
Maximum Lead Temperature for Soldering Purposes 1/8" from Case for 10 Seconds	$T_L$	260	°C

Characteristics		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Peak Repetitive Forward or Reverse Blocking Current ( $V_{AK}$ = Rated $V_{DRM}$ or $V_{RRM}$ ; $R_{GK}$ = 1.0 k $\Omega$ ) (Note 3)	$T_{J} = 25^{\circ}C$ $T_{J} = 110^{\circ}C$	I <sub>DRM</sub> I <sub>RRM</sub>	- -	_ _	10 500	μΑ
ON CHARACTERISTICS						
Peak Reverse Gate Blocking Voltage (I <sub>GR</sub> = 10 μA)		$V_{GRM}$	10	12.5	18	V
Peak Reverse Gate Blocking Current (V <sub>GR</sub> = 10 V)		I <sub>RGM</sub>	_	-	1.2	μΑ
Peak Forward On–State Voltage (Note 4) (I <sub>TM</sub> = 16 A)		$V_{TM}$	-	1.4	1.8	V
Gate Trigger Current (Continuous dc) (Note 5) $(V_D = 12 \text{ V}, \text{ R}_L = 100 \Omega)$	$T_J = 25^{\circ}C$ $T_J = -40^{\circ}C$	I <sub>GT</sub>	5.0 –	12 -	200 300	μΑ
Gate Trigger Voltage (Continuous dc) (Note 5) $(V_D = 12 \text{ V}, \text{ R}_L = 100 \Omega)$	$T_J = 25^{\circ}C$ $T_J = -40^{\circ}C$ $T_J = 110^{\circ}C$	V <sub>GT</sub>	0.45 - 0.2	0.65 - -	1.0 1.5 –	V
Holding Current (V <sub>D</sub> = 12 V, Initiating Current = 200 mA, Gate Open)	T <sub>J</sub> = 25°C T <sub>J</sub> = -40°C	Ін	0.5 -	1.0	6.0 10	mA
Latching Current $(V_D = 12 \text{ V}, I_G = 2.0 \text{ mA})$	T <sub>J</sub> = 25°C T <sub>J</sub> = -40°C	ΙL	0.5 -	1.0	6.0 10	mA
Total Turn–On Time (Source Voltage = 12 V, $R_S = 6.0 \text{ k}\Omega$ , $I_T = 16 \text{ A(pk)}$ , $R_C = 10 \text{ A(pk)}$ , $R$		tgt	I	2.0	5.0	μS
DYNAMIC CHARACTERISTICS						
Critical Rate of Rise of Off–State Voltage ( $V_D = 0.67 \text{ X Rated } V_{DRM}$ , Exponential Waveform, $R_{GK} = 1.0 \text{ k}\Omega$ , $T_{LI} = 110^{\circ}\text{C}$ )		dv/dt	2.0	10	-	V/μs

<sup>2.</sup> Surface mounted on minimum recommended pad size.

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
MCR8DSMT4	DPAK	
MCR8DSMT4G	DPAK (Pb-Free)	0500 / Tana & Basi
MCR8DSNT4	DPAK	2500 / Tape & Reel
MCR8DSNT4G	DPAK (Pb-Free)	

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

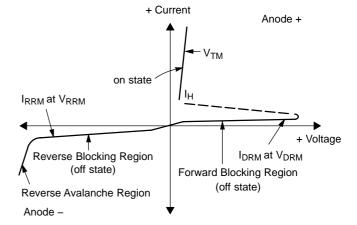
<sup>3.</sup> Ratings apply for negative gate voltage or R<sub>GK</sub> = 1.0 kΩ. Devices shall not have a positive gate voltage concurrently with a negative voltage on the anode. Devices should not be tested with a constant current source for forward and reverse blocking capability such that the voltage applied exceeds the rated blocking voltage.

<sup>4.</sup> Pulse Test; Pulse Width ≤ 2.0 msec, Duty Cycle ≤ 2%.

<sup>5.</sup> R<sub>GK</sub> current not included in measurements.

# **Voltage Current Characteristic of SCR**

Symbol	Parameter
$V_{DRM}$	Peak Repetitive Off-State Forward Voltage
I <sub>DRM</sub>	Peak Forward Blocking Current
V <sub>RRM</sub>	Peak Repetitive Off-State Reverse Voltage
I <sub>RRM</sub>	Peak Reverse Blocking Current
$V_{TM}$	Peak On-State Voltage
I <sub>H</sub>	Holding Current



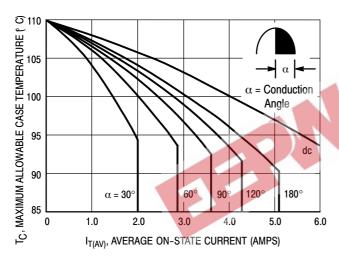


Figure 1. Average Current Derating

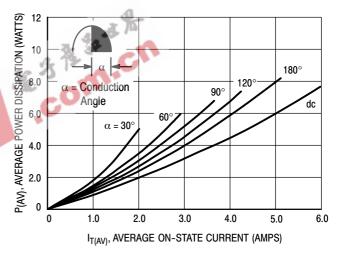
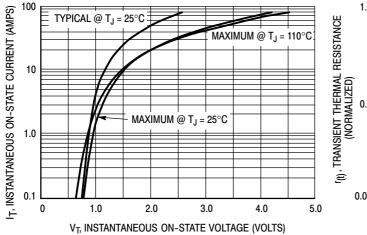


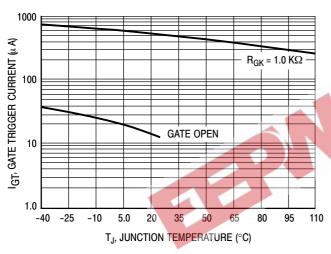
Figure 2. On-State Power Dissipation



0.01 0.1 1.0 10 100 1000 10 K t, TIME (ms)

Figure 3. On-State Characteristics

Figure 4. Transient Thermal Response



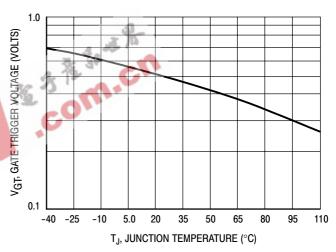
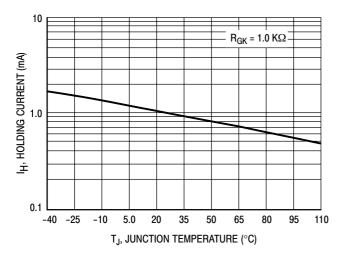


Figure 5. Typical Gate Trigger Current versus Junction Temperature

Figure 6. Typical Gate Trigger Voltage versus Junction Temperature



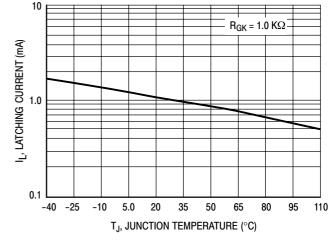


Figure 7. Typical Holding Current versus Junction Temperature

Figure 8. Typical Latching Current versus Junction Temperature

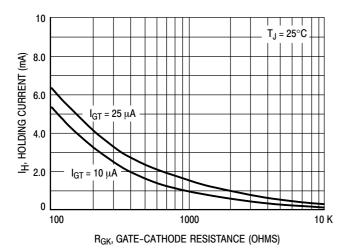
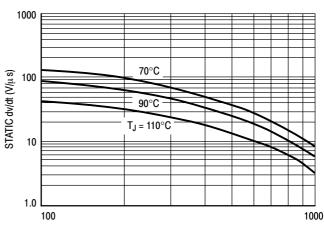


Figure 9. Holding Current versus Gate-Cathode Resistance



R<sub>GK</sub>, GATE-CATHODE RESISTANCE (OHMS)

Figure 10. Exponential Static dv/dt versus Gate-Cathode Resistance and Junction Temperature

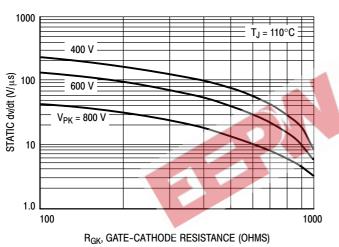
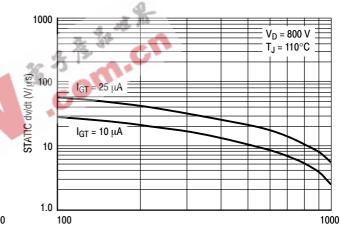


Figure 11. Exponential Static dv/dt versus Gate-Cathode Resistance and Peak Voltage

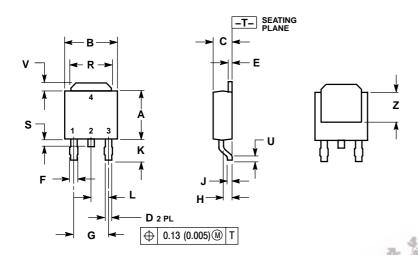


 $R_{\mbox{\scriptsize GK}},$  GATE-CATHODE RESISTANCE (OHMS)

Figure 12. Exponential Static dv/dt versus Gate-Cathode Resistance and Gate Trigger Current Sensitivity

#### PACKAGE DIMENSIONS

#### **DPAK** CASE 369C **ISSUE O**



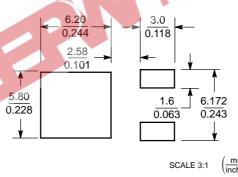
- NOTES:
  1. DIMENSIONING AND TOLERANCING
- PER ANSI Y14.5M, 1982.
  2. CONTROLLING DIMENSION: INCH.

	INCHES		MILLIN	ETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.245	5.97	6.22
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
Е	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.180	0.180 BSC		BSC
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
K	0.102	0.114	2.60	2.89
L	0.090 BSC		2.29	BSC
R	0.180	0.215	4.57	5.45
S	0.025	0.040	0.63	1.01
U	0.020		0.51	
٧	0.035	0.050	0.89	1.27
Z	0.155		3.93	

#### STYLE 4:

- PIN 1. CATHODE 2. ANODE 3. GATE 4. ANODE

# SOLDERING FOOTPRINT



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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